

## OptiMOS® Power-Transistor

### Feature

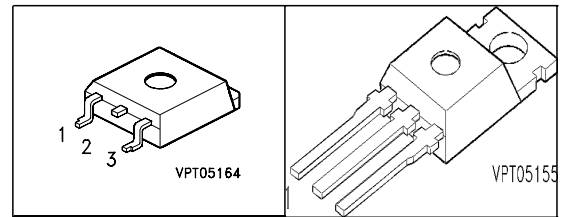
- N-Channel
- Enhancement mode
- 175°C operating temperature
- Avalanche rated
- dv/dt rated

### Product Summary

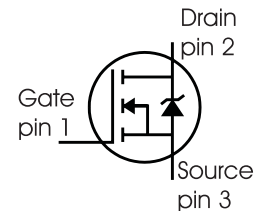
|              |     |    |
|--------------|-----|----|
| $V_{DS}$     | 55  | V  |
| $R_{DS(on)}$ | 9.1 | mΩ |
| $I_D$        | 80  | A  |

P-TO263-3-2

P-TO220-3-1



| Type          | Package     | Ordering Code | Marking |
|---------------|-------------|---------------|---------|
| SPP80N06S2-09 | P-TO220-3-1 | Q67060-S6025  | 2N0609  |
| SPB80N06S2-09 | P-TO263-3-2 | Q67060-S6027  | 2N0609  |



### Maximum Ratings, at $T_j = 25\text{ °C}$ , unless otherwise specified

| Parameter   | Symbol                | Value       | Unit  |
|---|-----------------------|-------------|-------|
| Continuous drain current<br>$T_C = 25\text{ °C}$ , <sup>1)</sup><br>$T_C = 100\text{ °C}$   | $I_D$                 | 80<br>80    | A     |
| Pulsed drain current<br>$T_C = 25\text{ °C}$  | $I_{D\text{ puls}}$   | 320         |       |
| Avalanche energy, single pulse<br>$I_D = 80\text{ A}$ , $V_{DD} = 25\text{ V}$ , $R_{GS} = 25\text{ Ω}$                             | $E_{AS}$              | 370         | mJ    |
| Reverse diode dv/dt<br>$I_S = 80\text{ A}$ , $V_{DS} = 44\text{ V}$ , $di/dt = 200\text{ A/μs}$ , $T_{j\text{max}} = 175\text{ °C}$ | dv/dt                 | 6           | kV/μs |
| Gate source voltage   | $V_{GS}$              | ±20         | V     |
| Power dissipation<br>$T_C = 25\text{ °C}$   | $P_{\text{tot}}$      | 190         | W     |
| Operating and storage temperature   | $T_j, T_{\text{stg}}$ | -55... +175 | °C    |
| IEC climatic category; DIN IEC 68-1   |                       | 55/175/56   |       |

**Thermal Characteristics**

| Parameter                                      | Symbol     | Values |      |      | Unit |
|--|------------|--------|------|------|------|
|  |            | min.   | typ. | max. |      |
| <b>Characteristics</b>                         |            |        |      |      |      |
| Thermal resistance, junction - case            | $R_{thJC}$ | -      | -    | 0.8  | K/W  |
| Thermal resistance, junction - ambient, leaded | $R_{thJA}$ | -      | -    | 62   |      |
| SMD version, device on PCB:                    | $R_{thJA}$ |        |      |      |      |
| @ min. footprint                               |            | -      | -    | 62   |      |
| @ 6 cm <sup>2</sup> cooling area <sup>2)</sup> |            | -      | -    | 40   |      |

**Electrical Characteristics**, at  $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified

| Parameter  | Symbol        | Values |      |      | Unit       |
|--|---------------|--------|------|------|------------|
|  |               | min.   | typ. | max. |            |
| <b>Static Characteristics</b>  |               |        |      |      |            |
| Drain-source breakdown voltage<br>$V_{GS}=0V, I_D=1mA$   | $V_{(BR)DSS}$ | 55     | -    | -    | V          |
| Gate threshold voltage, $V_{GS} = V_{DS}$<br>$I_D = 125\ \mu A$  | $V_{GS(th)}$  | 2.1    | 3    | 4    |            |
| Zero gate voltage drain current<br>$V_{DS}=55V, V_{GS}=0V, T_j=25^\circ C$<br>$V_{DS}=55V, V_{GS}=0V, T_j=125^\circ C$ | $I_{DSS}$     | -      | 0.01 | 1    | $\mu A$    |
|  |               | -      | 1    | 100  |            |
| Gate-source leakage current<br>$V_{GS}=20V, V_{DS}=0V$   | $I_{GSS}$     | -      | 1    | 100  | nA         |
| Drain-source on-state resistance<br>$V_{GS}=10V, I_D=50A$  | $R_{DS(on)}$  | -      | 7.8  | 9.1  | m $\Omega$ |

<sup>1</sup>Current limited by bondwire; with a  $R_{thJC} = 0.8\text{ K/W}$  the chip is able to carry  $I_D = 99A$  and calculated with max. source pin temperature of  $85^\circ C$ .

<sup>2</sup>Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6cm<sup>2</sup> (one layer, 70  $\mu m$  thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics, at  $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified

| Parameter | Symbol | Conditions | Values |      |      | Unit |
|-----------|--------|------------|--------|------|------|------|
|           |        |            | min.   | typ. | max. |      |

**Dynamic Characteristics**

|                              |              |   |    |      |      |    |
|------------------------------|--------------|---|----|------|------|----|
| Transconductance             | $g_{fs}$     | $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$ ,<br>$I_D = 80\text{A}$                     | 34 | 68   | -    | S  |
| Input capacitance            | $C_{iss}$    | $V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ ,<br>$f = 1\text{MHz}$                       | -  | 2325 | 2900 | pF |
| Output capacitance           | $C_{oss}$    |   | -  | 610  | 760  |    |
| Reverse transfer capacitance | $C_{rss}$    |   | -  | 160  | 240  |    |
| Turn-on delay time           | $t_{d(on)}$  | $V_{DD} = 30\text{V}$ , $V_{GS} = 10\text{V}$ ,<br>$I_D = 80\text{A}$ , $R_G = 4.7\Omega$ | -  | 14   | 21   | ns |
| Rise time                    | $t_r$        |   | -  | 29   | 44   |    |
| Turn-off delay time          | $t_{d(off)}$ |   | -  | 39   | 58   |    |
| Fall time                    | $t_f$        |   | -  | 28   | 42   |    |

**Gate Charge Characteristics**

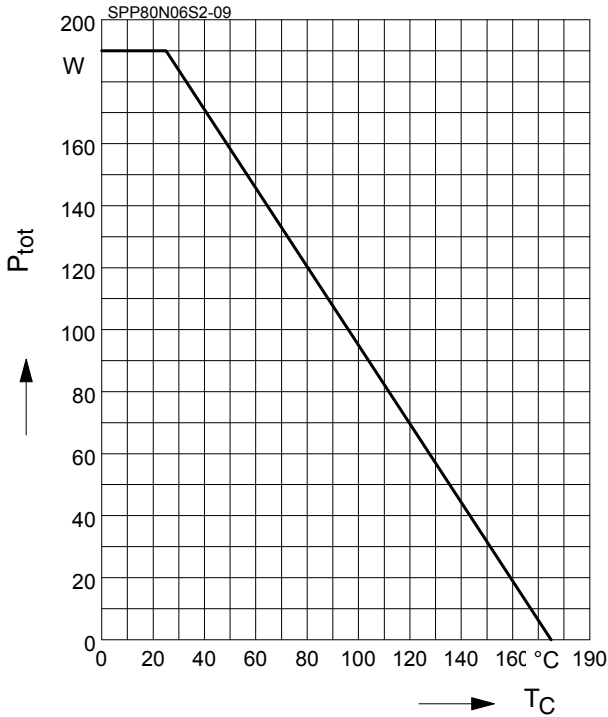
|                       |                 |  |   |     |    |    |
|-----------------------|-----------------|--|---|-----|----|----|
| Gate to source charge | $Q_{gs}$        | $V_{DD} = 44\text{V}$ , $I_D = 80\text{A}$                                   | - | 13  | 16 | nC |
| Gate to drain charge  | $Q_{gd}$        |  | - | 27  | 40 |    |
| Gate charge total     | $Q_g$           | $V_{DD} = 44\text{V}$ , $I_D = 80\text{A}$ ,<br>$V_{GS} = 0$ to $10\text{V}$ | - | 62  | 78 |    |
| Gate plateau voltage  | $V_{(plateau)}$ | $V_{DD} = 44\text{V}$ , $I_D = 80\text{A}$                                   | - | 5.8 | -  | V  |

**Reverse Diode**

|  |          |   |   |     |     |    |
|--|----------|---|---|-----|-----|----|
| Inverse diode continuous forward current | $I_S$    | $T_C = 25\text{ }^\circ\text{C}$  | - | -   | 80  | A  |
| Inverse diode direct current, pulsed     | $I_{SM}$ |   | - | -   | 320 |    |
| Inverse diode forward voltage            | $V_{SD}$ | $V_{GS} = 0\text{V}$ , $I_F = 80\text{A}$                                 | - | 0.9 | 1.3 | V  |
| Reverse recovery time                    | $t_{rr}$ | $V_R = 30\text{V}$ , $I_F = I_S$ ,<br>$di_F/dt = 100\text{A}/\mu\text{s}$ | - | 50  | 63  | ns |
| Reverse recovery charge                  | $Q_{rr}$ |   | - | 76  | 95  | nC |

### 1 Power dissipation

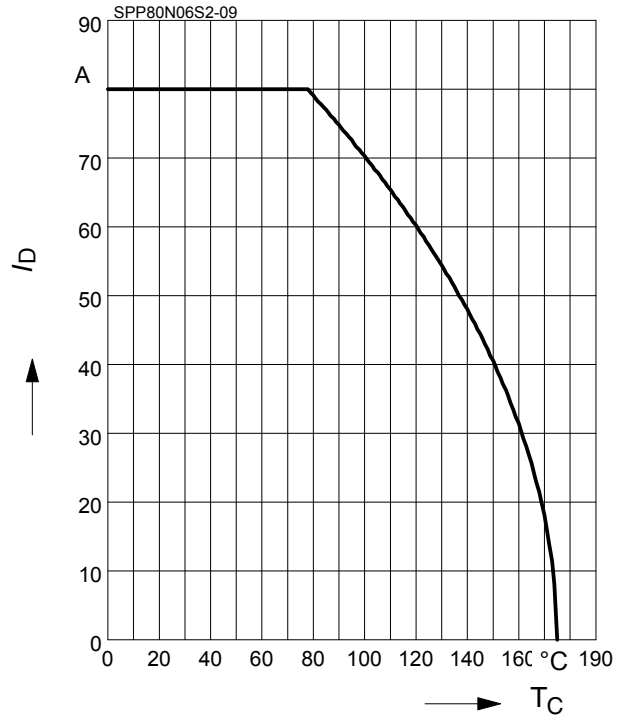
$$P_{tot} = f(T_C)$$



### 2 Drain current

$$I_D = f(T_C)$$

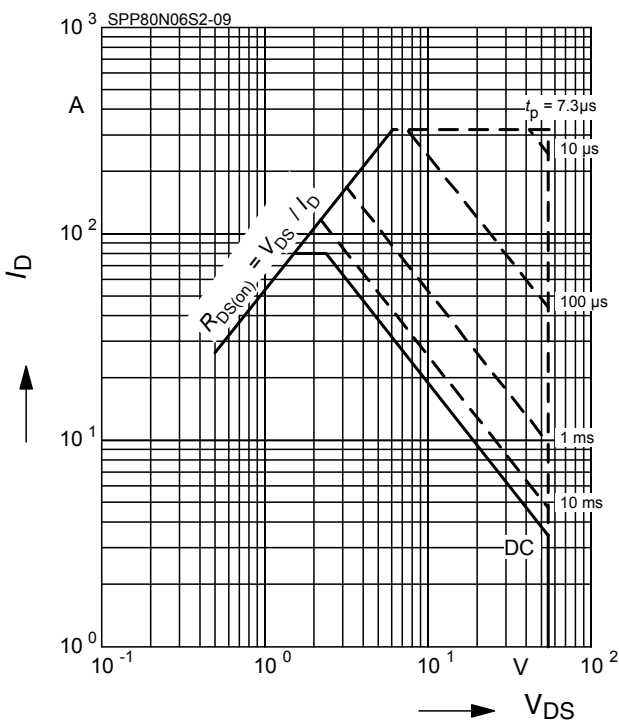
parameter:  $V_{GS} \geq 10 \text{ V}$



### 3 Safe operating area

$$I_D = f(V_{DS})$$

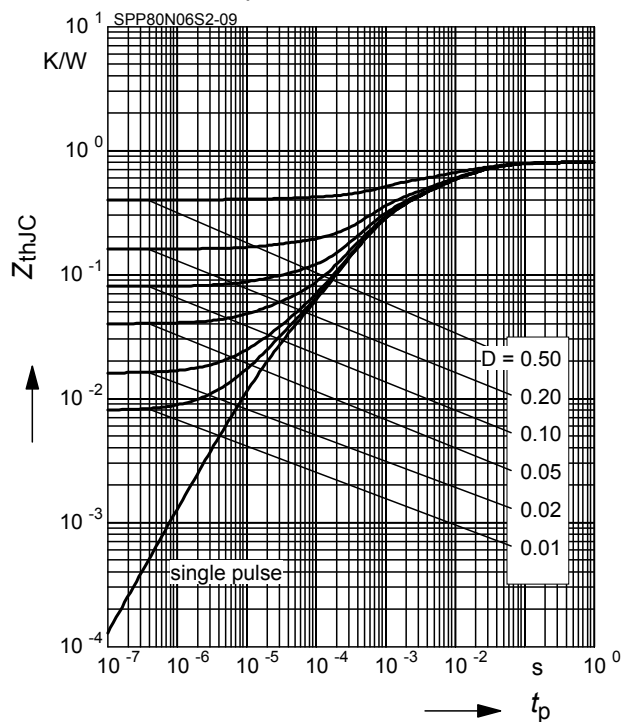
parameter:  $D = 0$ ,  $T_C = 25 \text{ °C}$



### 4 Transient thermal impedance

$$Z_{thJC} = f(t_p)$$

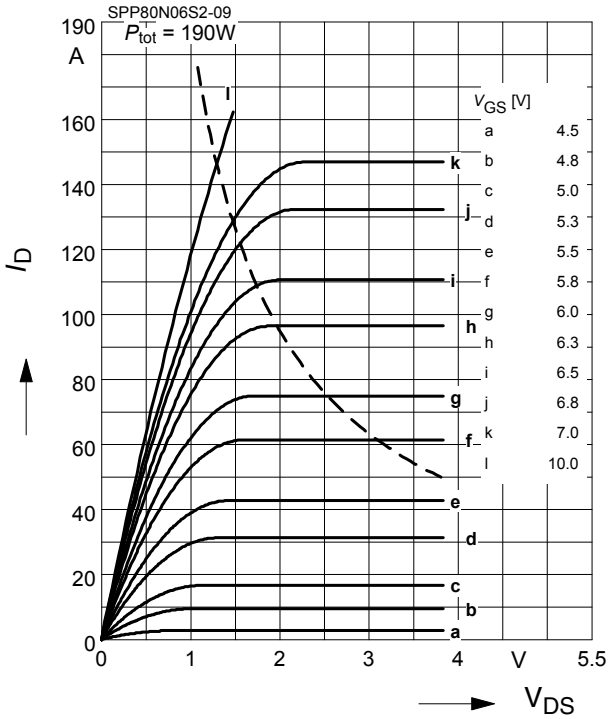
parameter:  $D = t_p/T$



**5 Typ. output characteristic**

$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$

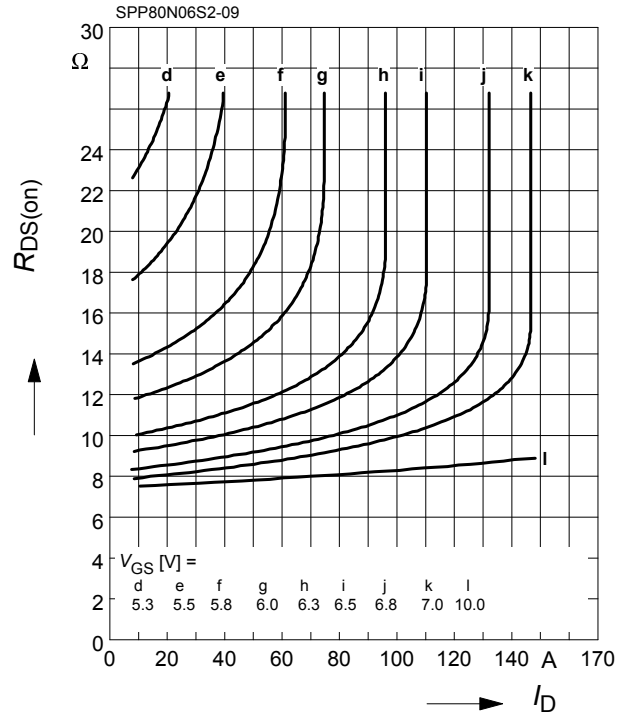
parameter:  $t_p = 80 \mu\text{s}$



**6 Typ. drain-source on resistance**

$R_{DS(on)} = f(I_D)$

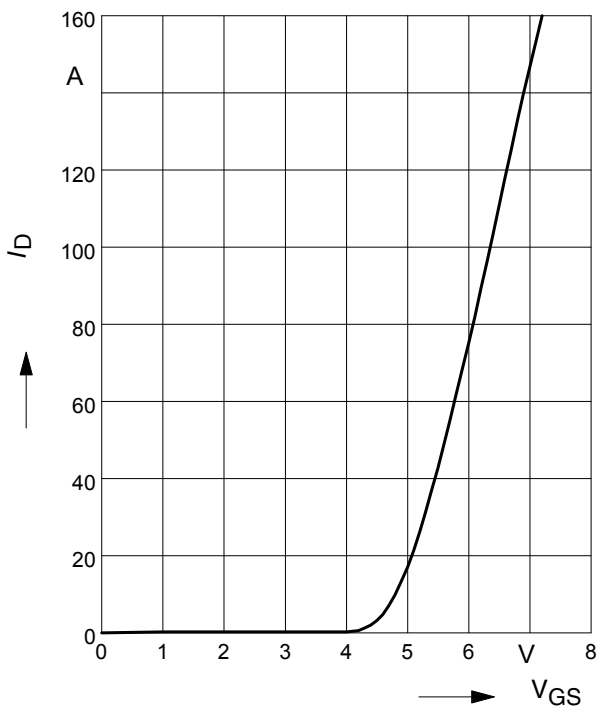
parameter:  $V_{GS}$



**7 Typ. transfer characteristics**

$I_D = f(V_{GS}); V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$

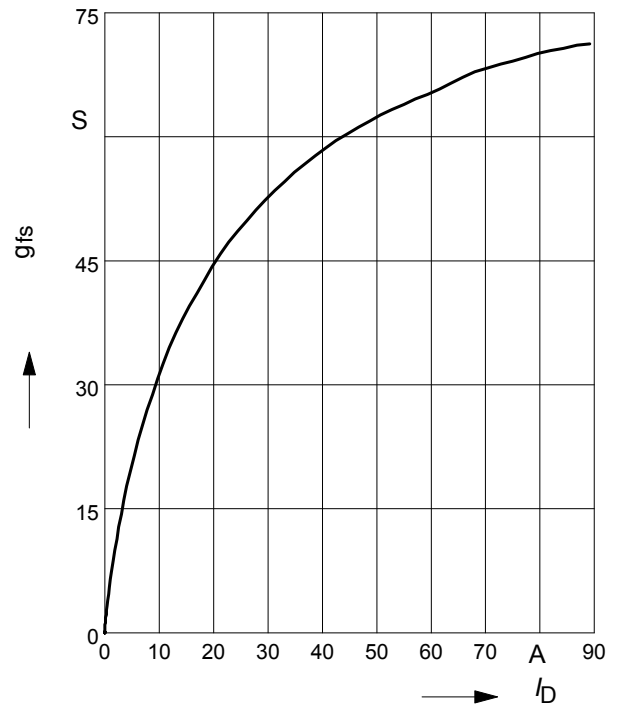
parameter:  $t_p = 80 \mu\text{s}$



**8 Typ. forward transconductance**

$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$

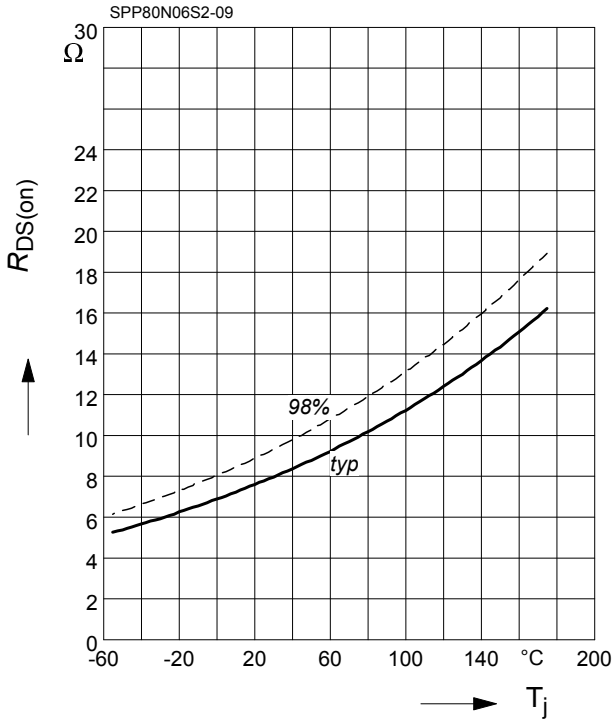
parameter:  $g_{fs}$



**9 Drain-source on-state resistance**

$$R_{DS(on)} = f(T_j)$$

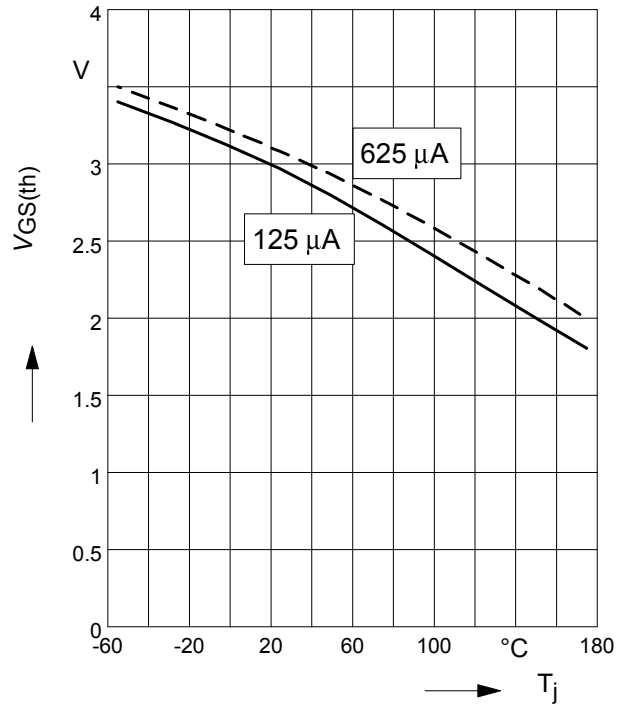
parameter :  $I_D = 50 \text{ A}$ ,  $V_{GS} = 10 \text{ V}$



**10 Typ. gate threshold voltage**

$$V_{GS(th)} = f(T_j)$$

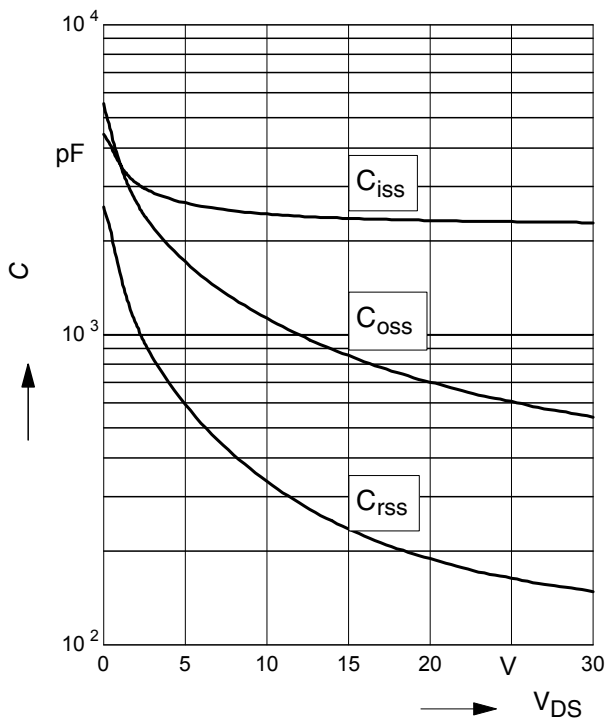
parameter:  $V_{GS} = V_{DS}$



**11 Typ. capacitances**

$$C = f(V_{DS})$$

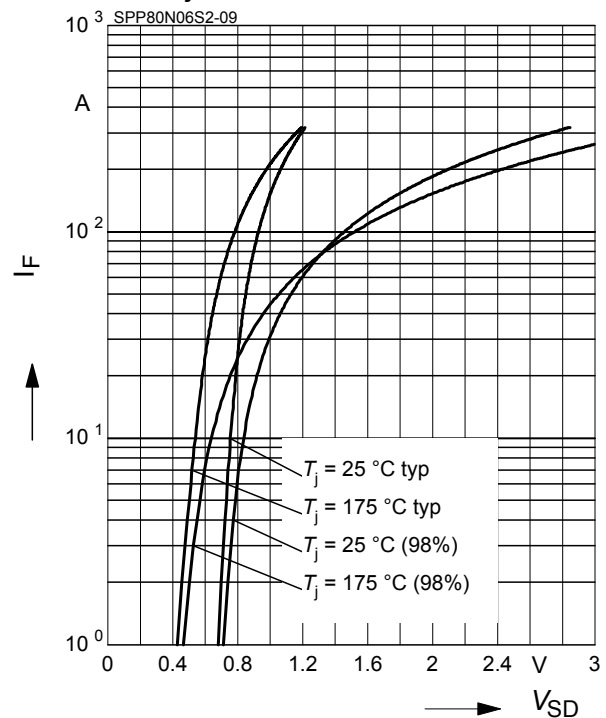
parameter:  $V_{GS}=0\text{V}$ ,  $f=1 \text{ MHz}$



**12 Forward character. of reverse diode**

$$I_F = f(V_{SD})$$

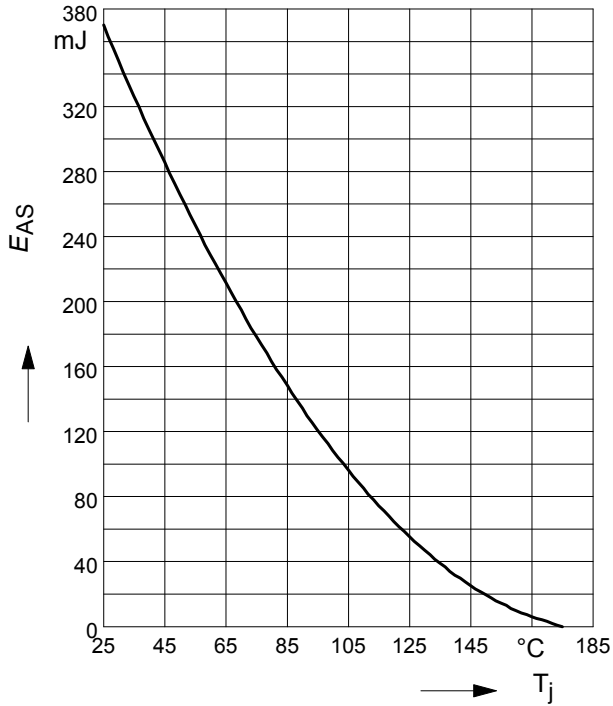
parameter:  $T_j$ ,  $t_p = 80 \mu\text{s}$



**13 Typ. avalanche energy**

$$E_{AS} = f(T_j)$$

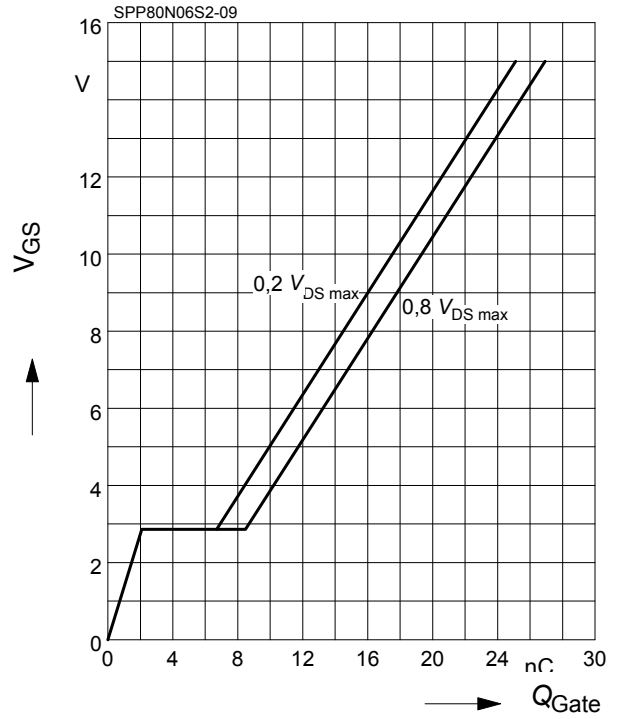
par.:  $I_D = 80 \text{ A}$  ,  $V_{DD} = 25 \text{ V}$ ,  $R_{GS} = 25 \Omega$



**14 Typ. gate charge**

$$V_{GS} = f(Q_{Gate})$$

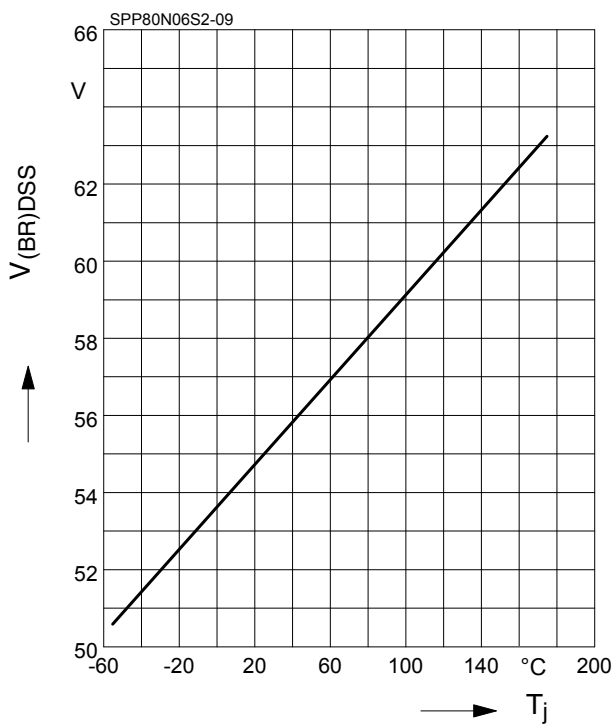
parameter:  $I_D = 80 \text{ A}$  pulsed



**15 Drain-source breakdown voltage**

$$V_{(BR)DSS} = f(T_j)$$

parameter:  $I_D = 10 \text{ mA}$



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